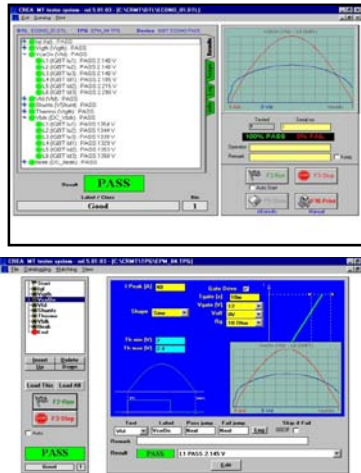


### MT100S SERIES CONFIGURATIONS

	MT100S-23-30-FLX08	MT100S-23-08-FLX30	MT100S-23-06-FLX08	MT100S-23-02-FLX32	MT100-STD23-02-FLX20	MT100-STD23-02-FLX08
<b>Current Generator:</b> Standard tests: VF, VT, VDSon, VCEon, Vt <sub>sm</sub> , Vf <sub>sm</sub> ,	3000 Amp 10V			200Amp 10V		
<b>Voltage Generator</b> Standard tests :V <sub>rrm</sub> , V <sub>d</sub> rm, I <sub>rrm</sub> , I <sub>d</sub> rm, B <sub>v</sub> ces, I <sub>c</sub> es	2300V/50mA					
<b>Gate parameters measurement generator:</b> Standard tests: I <sub>gt</sub> , V <sub>gt</sub> , I <sub>h</sub> , I <sub>l</sub> , V <sub>g</sub> eth, V <sub>g</sub> sth, I <sub>ges</sub> , I <sub>gss</sub>	± 30V from 10µA F.S. to 1A F.S. 6 ranges					
<b>Matrix Scanner</b>	kelvin test check					
Power channels	8	3	8	32	20	8
Measure channels	16	4	8	32	20	8
Gates channels	16	4	8	32	20	8



- Currents up to **200A** each channel and Voltages up to **2.3kV** can be switched in a single Paralleling (setting by layout environment) up to **5 power channel** to increase current
- **Results collection**, exporting and statistical analysis
  - **Enhanced Testprogram editor** features: the same parameters set can apply to different junctions; Testprograms can be checked and debugged.
  - **Flexible Testprogram**: test flow can be made dependent on partial results (**Jump on Pass/Fail**)
  - **Classes** can be defined upon test results using the Matching **editor**.
  - **Waveform inspection**
- Binning result for automation interface handshaking

Tests compliant to IEC 60647-2/60647-9